



**Oregon State
University**

Practical Challenges and Failure Modes During Fabrication of Haynes 230 Micro-Pin Solar Receivers for High Temperature sCO₂ Operation

P. S. McNeff, B. K. Paul, O. N. Dogan, K. A. Rozman,
S. Kissick, H. Wang, M. K. Drost and B. M. Fronk

3rd European Supercritical CO₂ Conference

Paper # 2019-sCO₂.eu-157

September 19, 2019

COLLEGE OF
ENGINEERING

School of Mechanical, Industrial, and
Manufacturing Engineering

Outline

1. Concept and Methods
2. Failure Modes
3. Failure Mitigation
4. Conclusions

Concentrated Solar Thermal Power

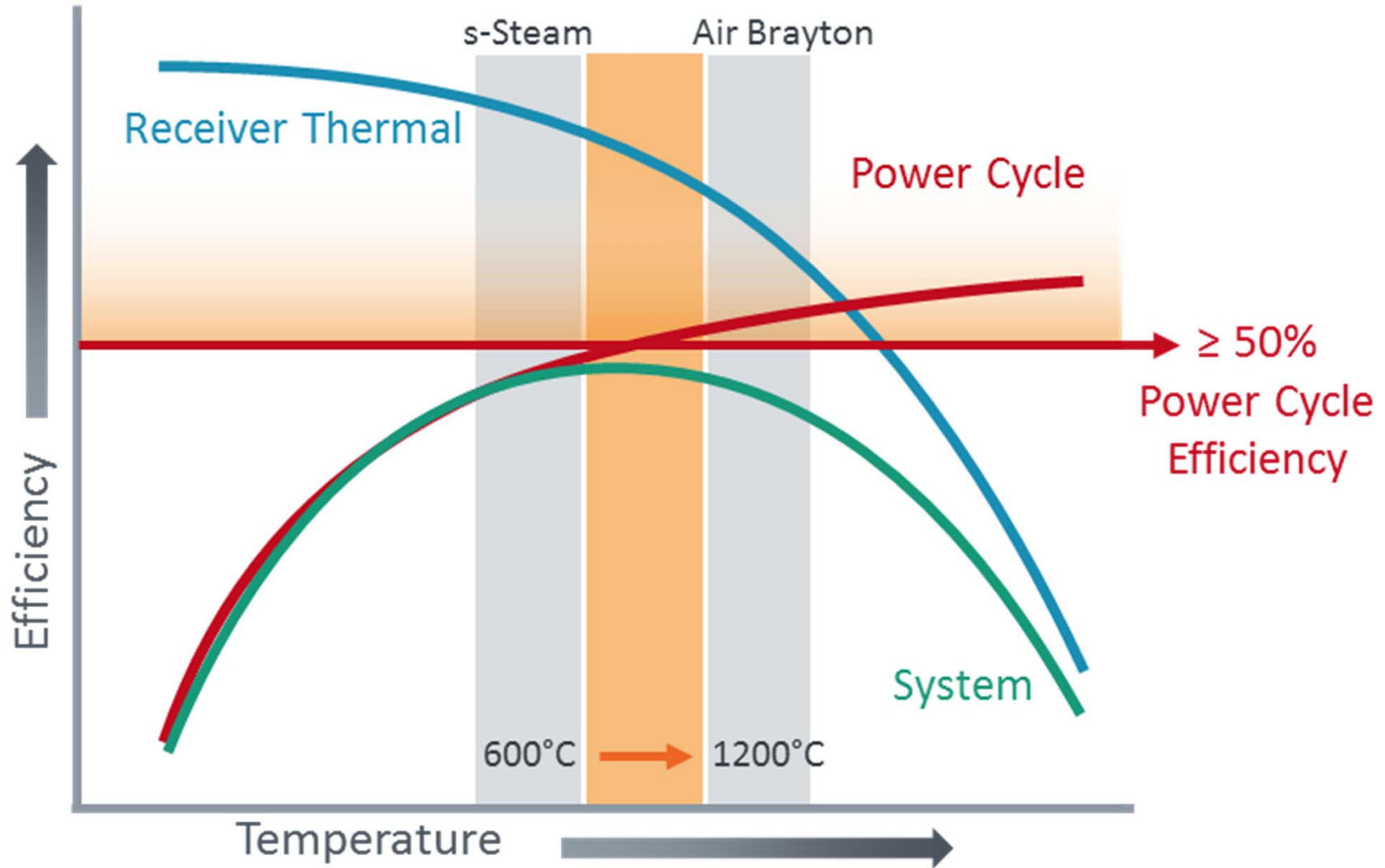


Primary Challenge

$$\eta = 1 - \frac{T_c}{T_H}$$

$$q''_{loss} \propto T_s^4$$

Supercritical Brayton Cycle



sCO₂ High Flux Receiver Development

Project Goals

- Receiver efficiency > 90%
- sCO₂ from 550°C to 720°C
- $P = 250$ bar
- < \$150/kW_{th}
- > 10,000 cycle life

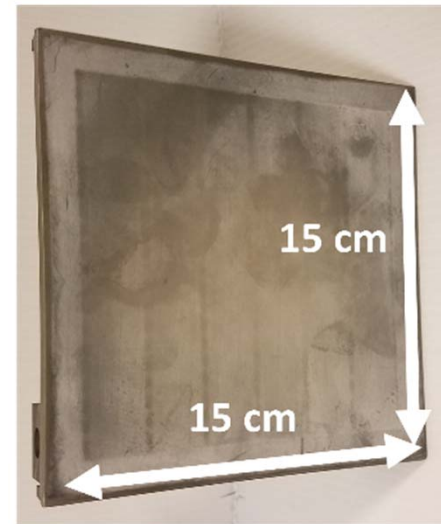
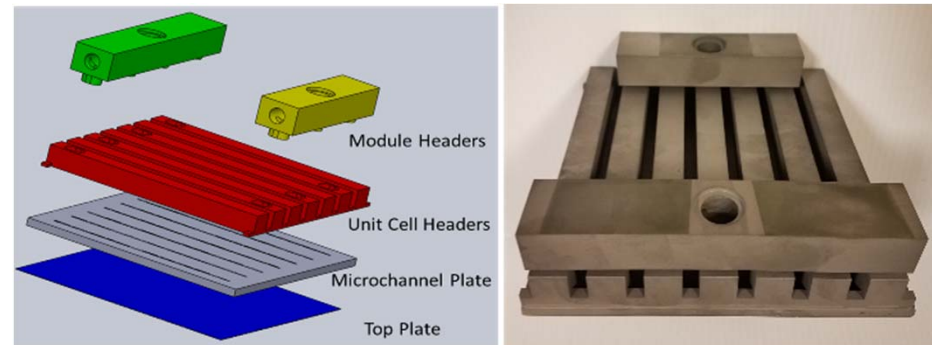


Oregon State
University

UC DAVIS



Pacific Northwest
NATIONAL LABORATORY



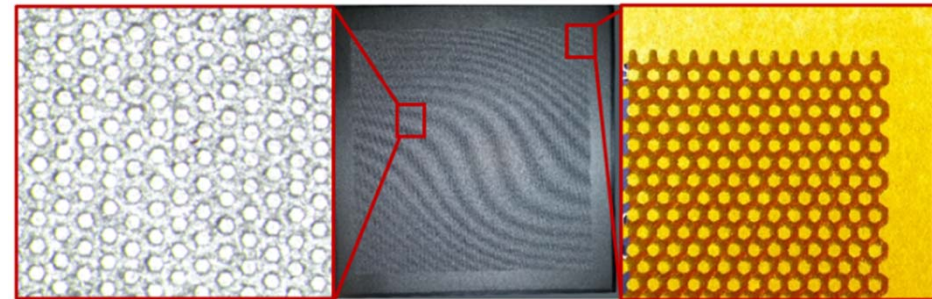
Micro-Pin Receiver Concept

Advantages

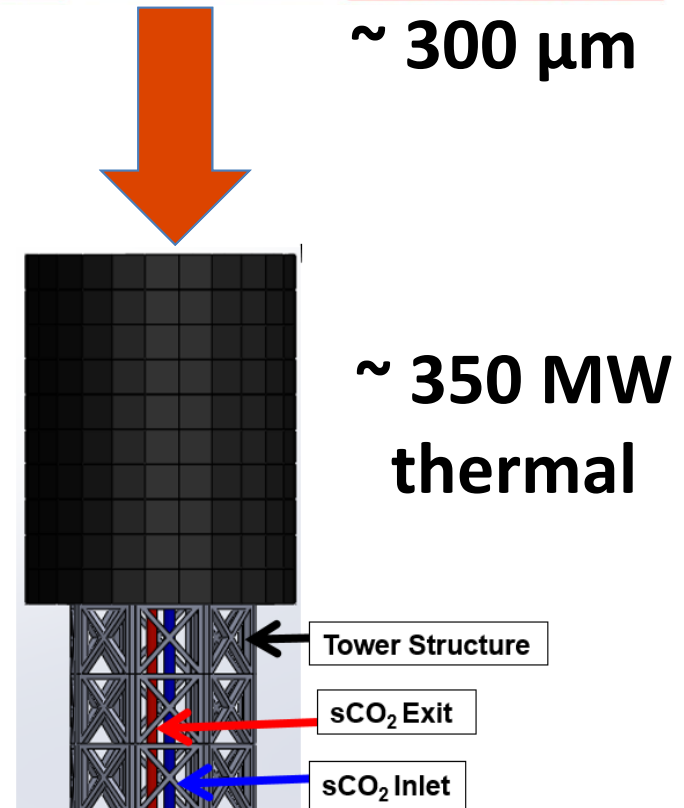
- $D_H \downarrow h \uparrow$
- Thin walls
- Reduced material
- Modularity

Challenges

- Thermal hydraulic
- Manufacturing
- Reliability

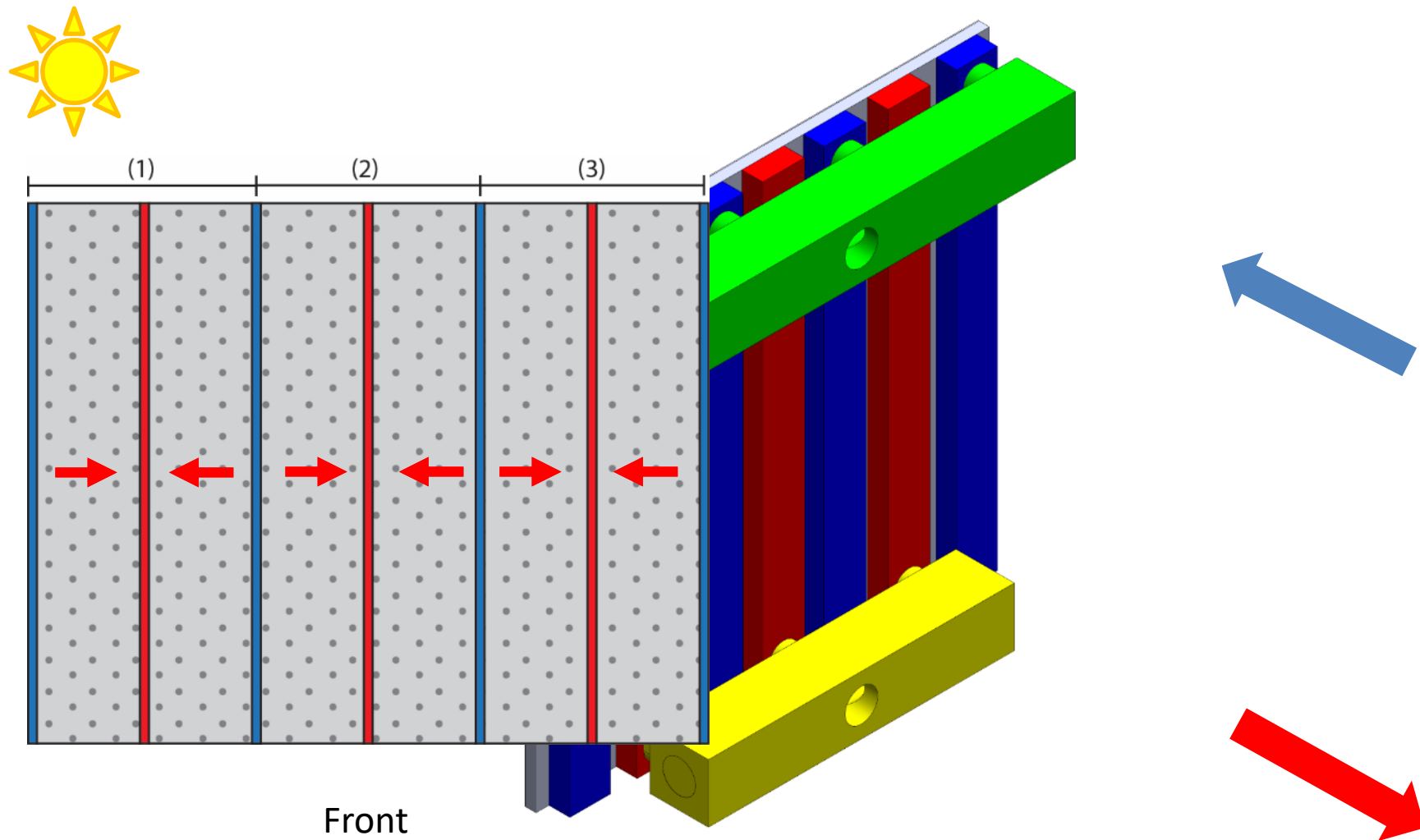


~ 300 μm



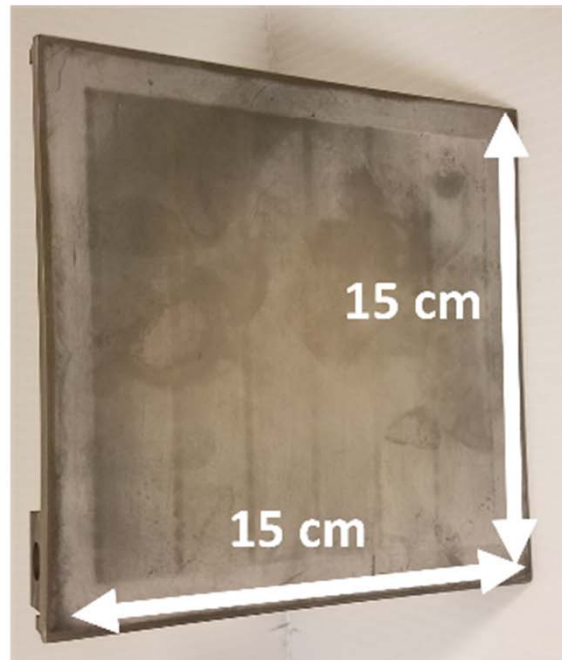
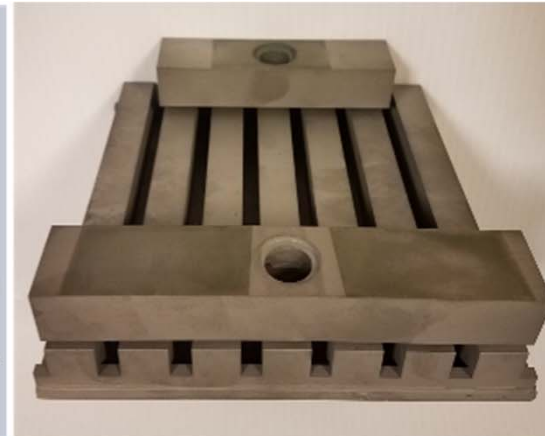
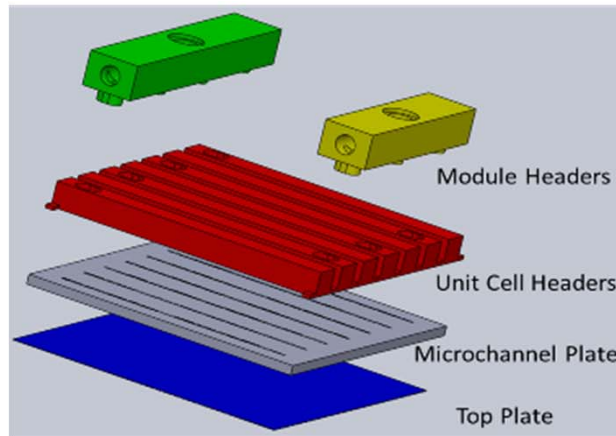
~ 350 MW
thermal

Module Design



Front

Prototype Development

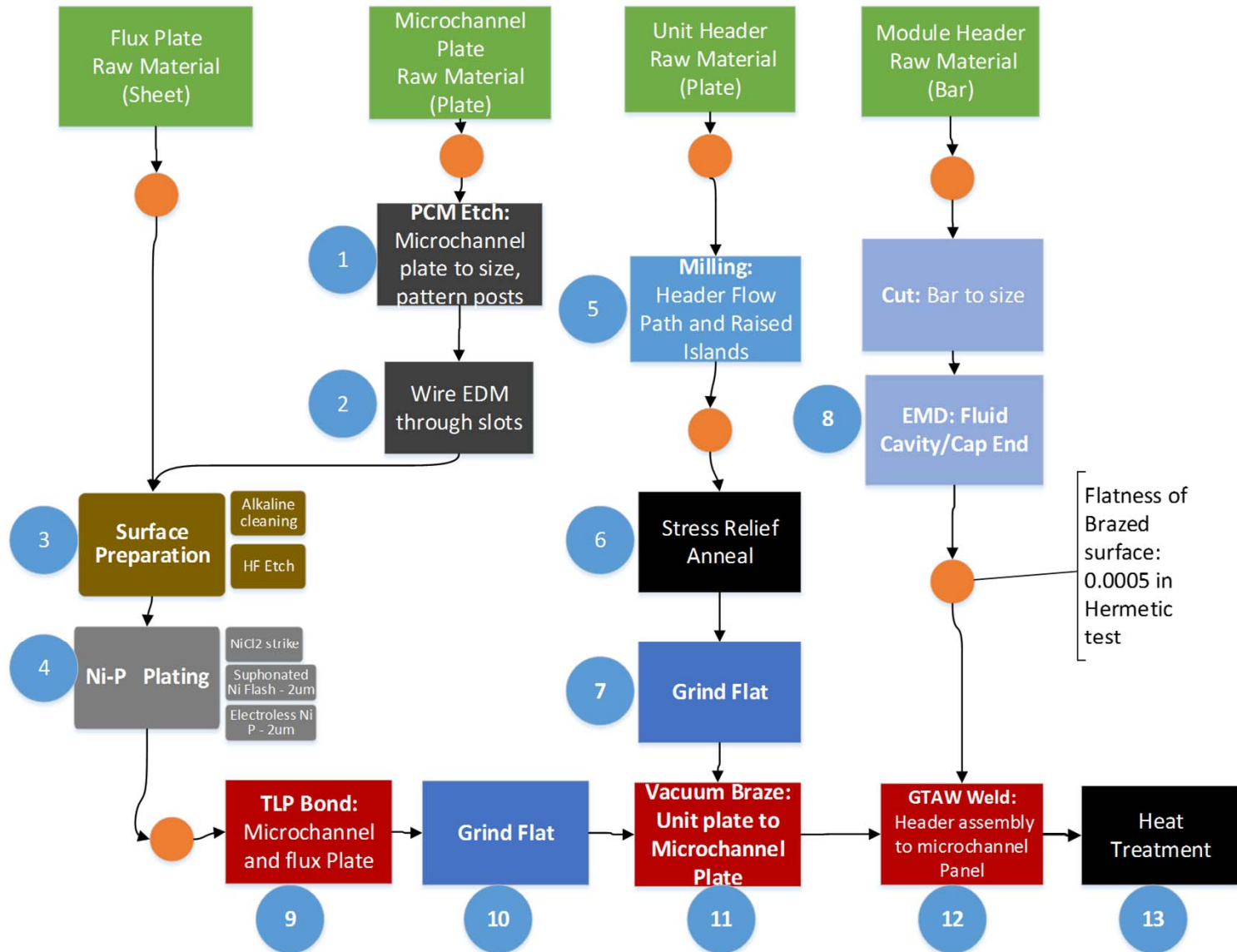


Material – Haynes 230

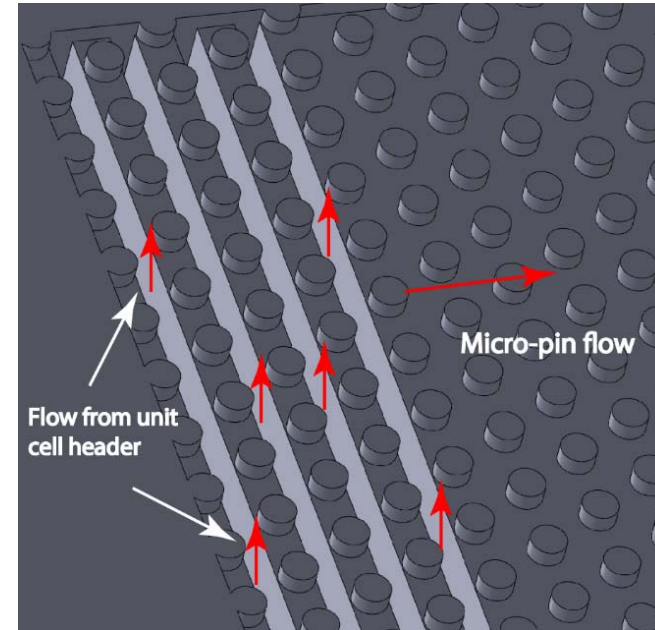
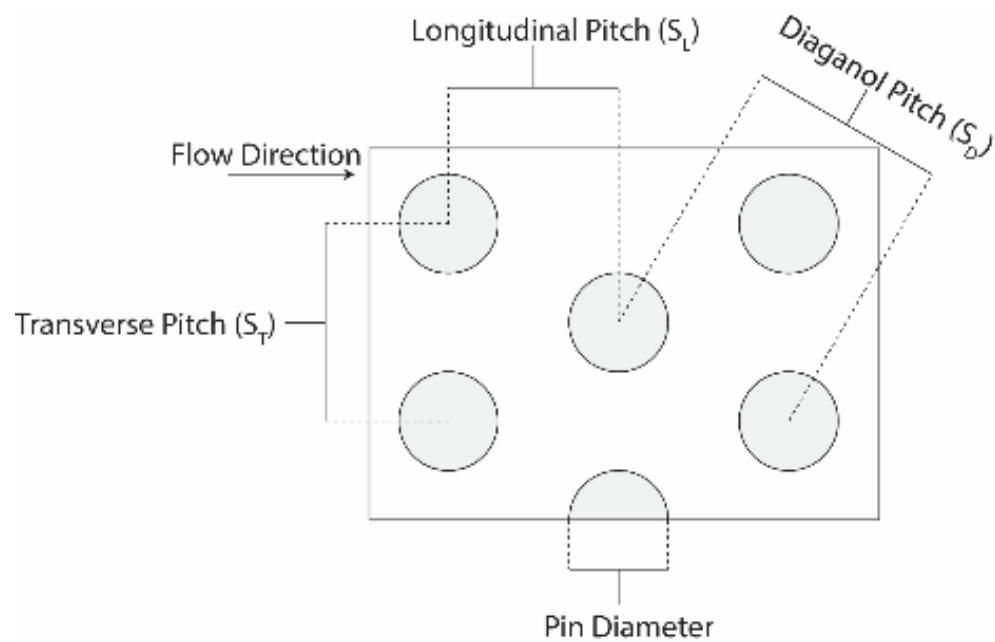
Component	Weight %
Nickel	57 (balance)
Chromium	22
Tungsten	14
Molybdenum	2
Iron	3 (max)
Cobalt	5 (max)
Manganese	0.5
Silicon	0.4
Niobium	0.5 (max)
Aluminum	0.3
Titanium	0.1 (max)
Carbon	0.1
Lanthanum	0.02
Boron	0.015 (max)

- Corrosion resistance
- Allowable stress at temperature
- Ability to TLP/diffusion bond
- Weldability
- Ability to photochemical etch
- Ability to procure in required form factors

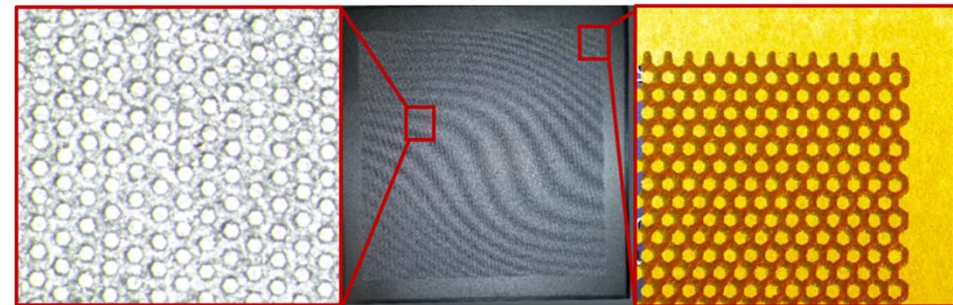
Fabrication Method



Fabrication Method – Pin Array

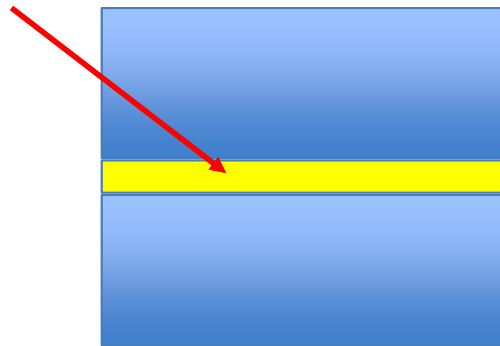


Variable Name	Dimension	Value
D_{pin}	Pin diameter	300 μm
h_{pin}	Pin height	150 μm
S_L	Longitudinal pitch	520 μm
S_T	Transverse pitch	600 μm
S_D	Diagonal pitch	600 μm

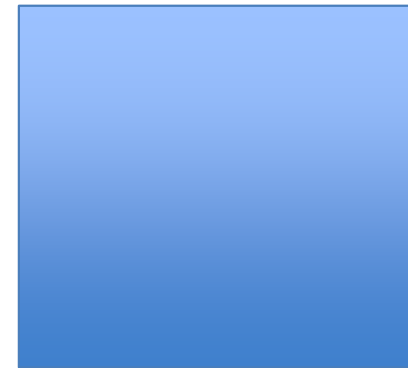


Fabrication Method – Transient Liquid Phase Bond

Interlayer with melting point depressant (P here)

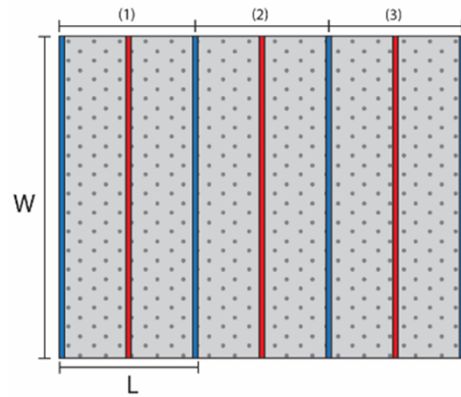


MPD diffuses into parent, isothermal solidification

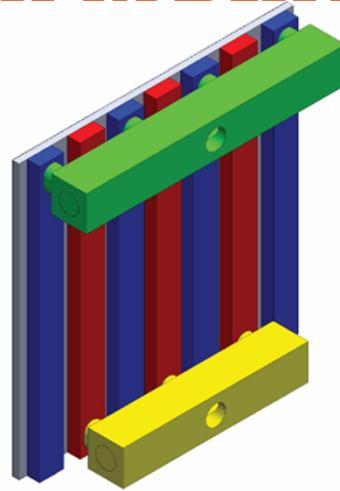


- First NiCl strike was applied to help increase adhesion.
- Then, a 2 μm sulfonated layer of pure nickel was electrically deposited, followed by a 2 μm electroless mid-phosphorus layer ($\sim 6\%$ P).
- This resulted in a phosphorous content of approximately 3% in the interlayer.
- The bonding temperature was 1150 $^{\circ}\text{C}$ at a vacuum pressure less than 1×10^{-5} torr for a dwell time of 4 hours.

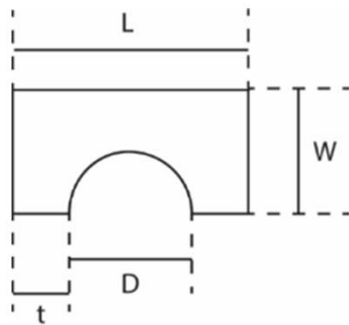
Fabrication Methods - Brazing



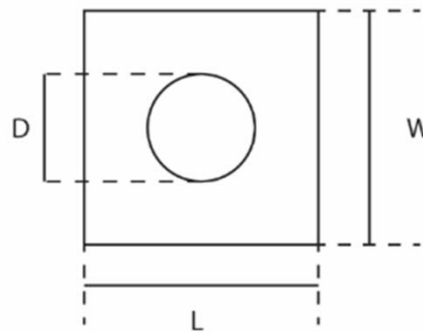
(A)



(B)



(C) Unit Cell Header



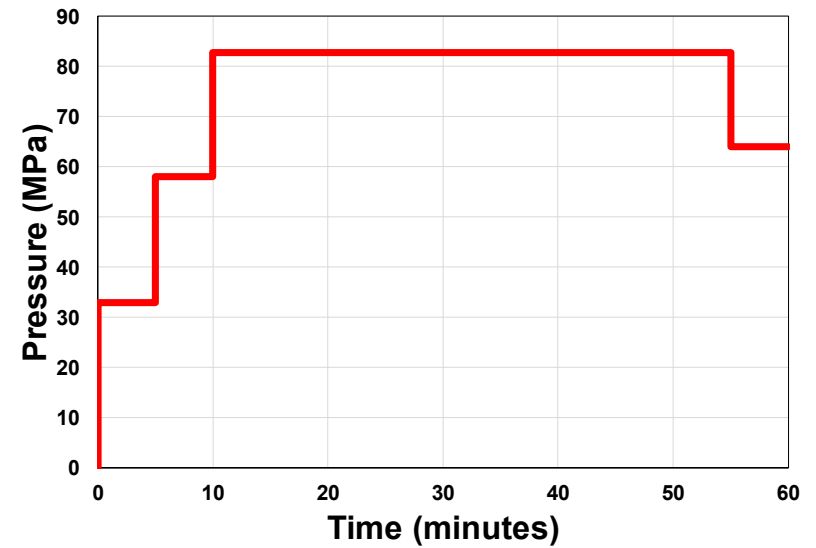
(D) Module Header

Step	Description
1	Ramp to 950 °C @ 5 °C per minute
2	1 st Hold: 950 °C for 1.5 hours
3	2 nd Hold: 1195 °C for 2.5 hours
4	Cool to 1100 °C (2 °C per min) in 1.5 mbar Argon
5	3 rd Hold: 1100 °C for 3.5 hours



Header	W (mm)	L (mm)	D (mm)	t (mm)
(A) Unit-cell header	8.125	16.25	6.25	5
(B) Module header	22.7	22.7	12.7	5

Proof Pressure Test

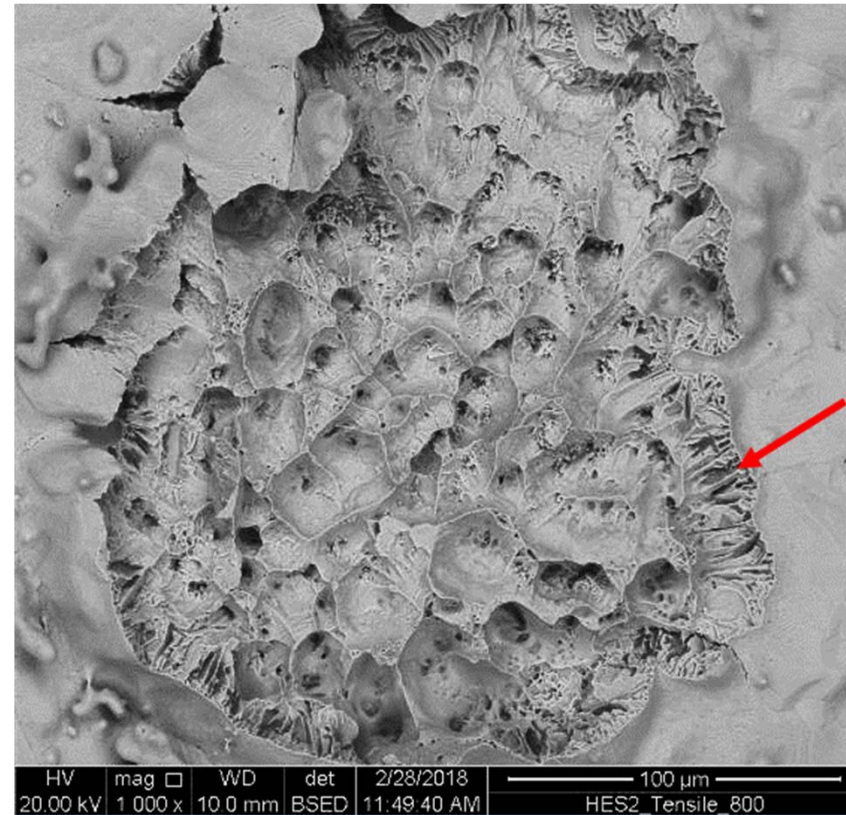
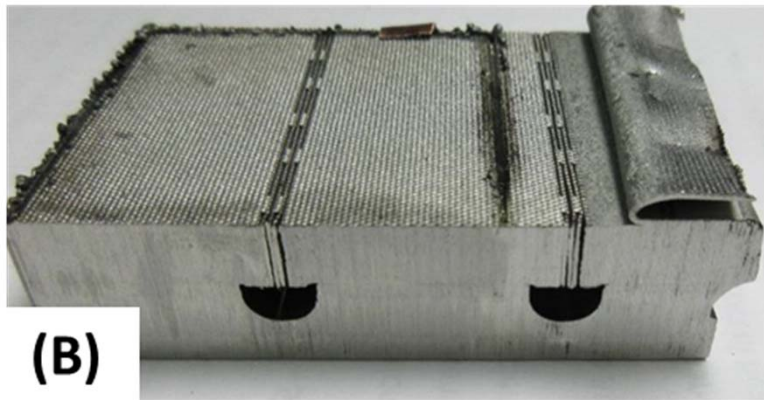
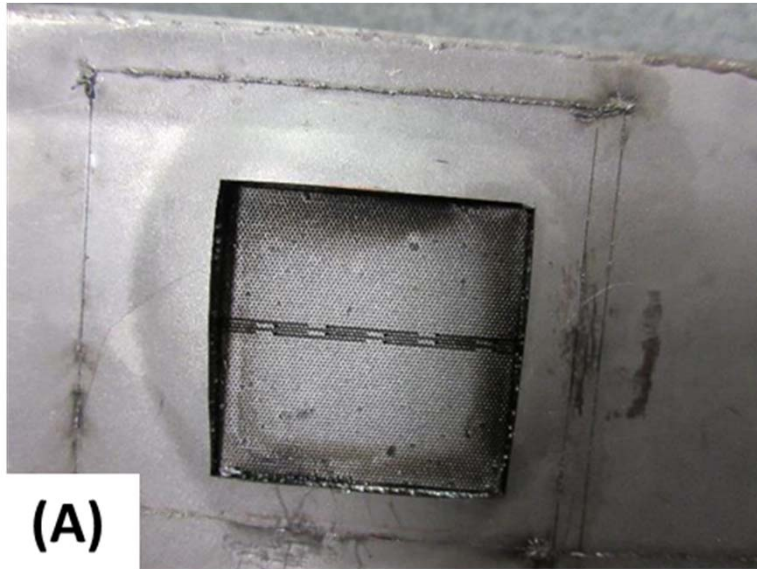


$$P = 1.3 \cdot MAWP \cdot \frac{\sigma_T}{\sigma_D}$$

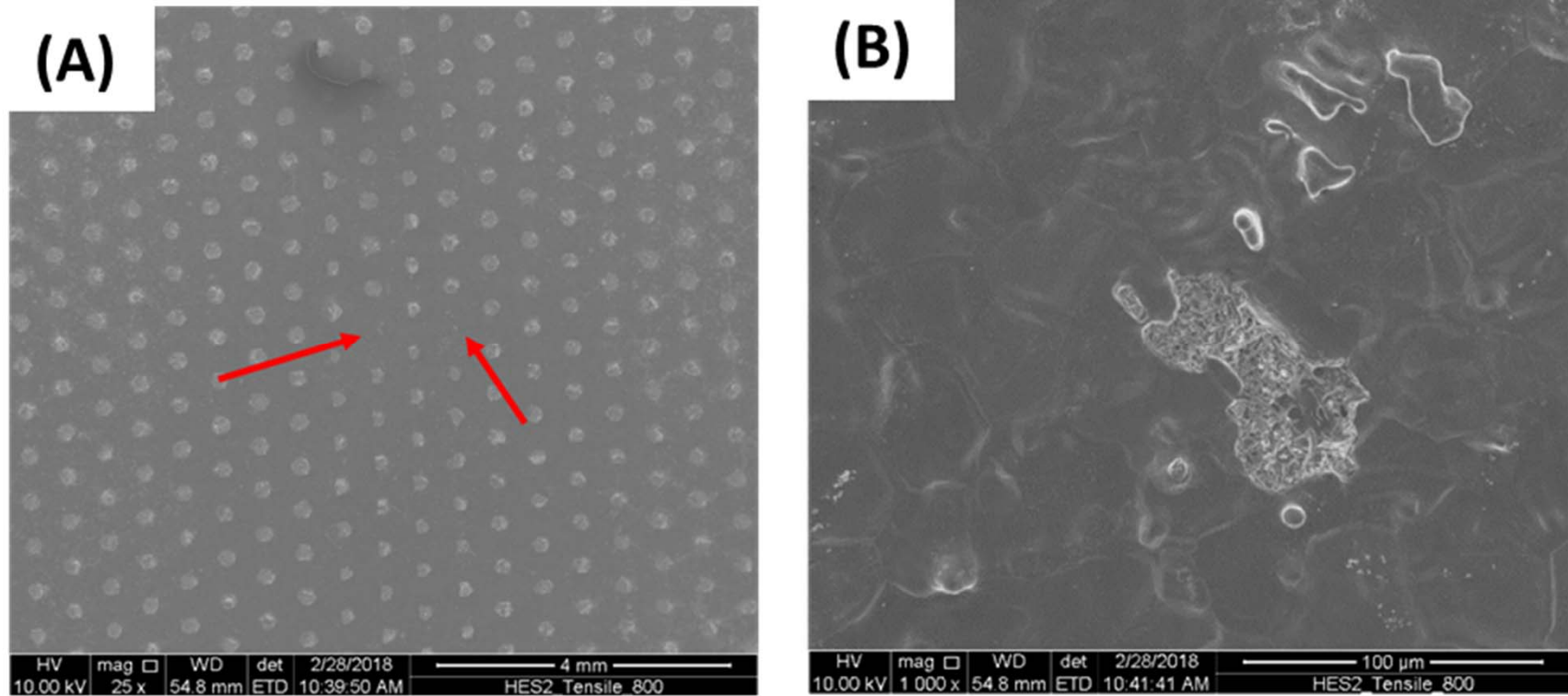
Failure Mode



Failure Mode Analysis

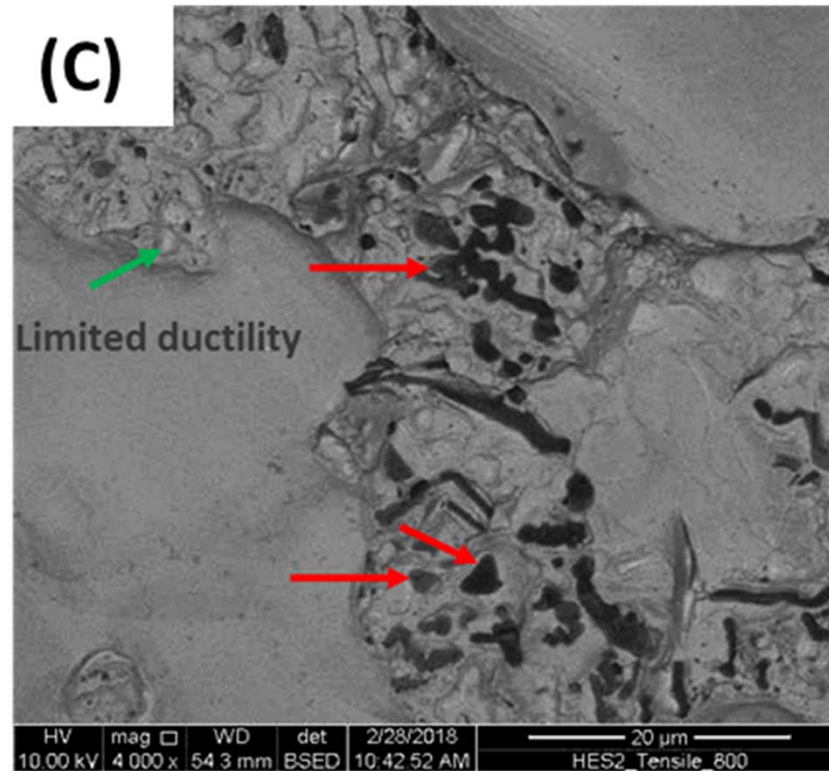


Failure Related to TLP



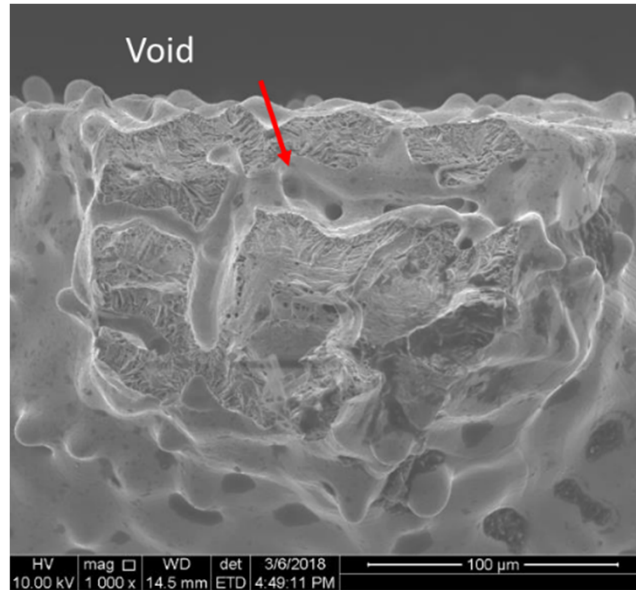
- Limited bonding in “missing pin”

Failure Related to TLP



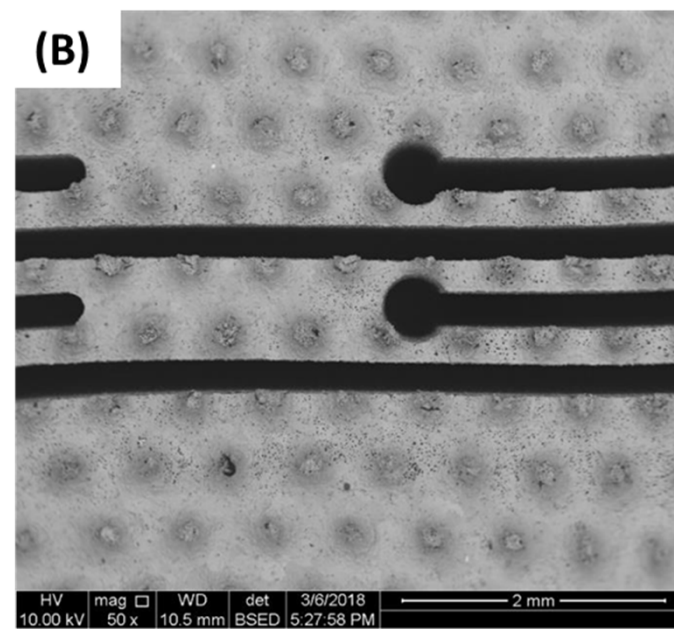
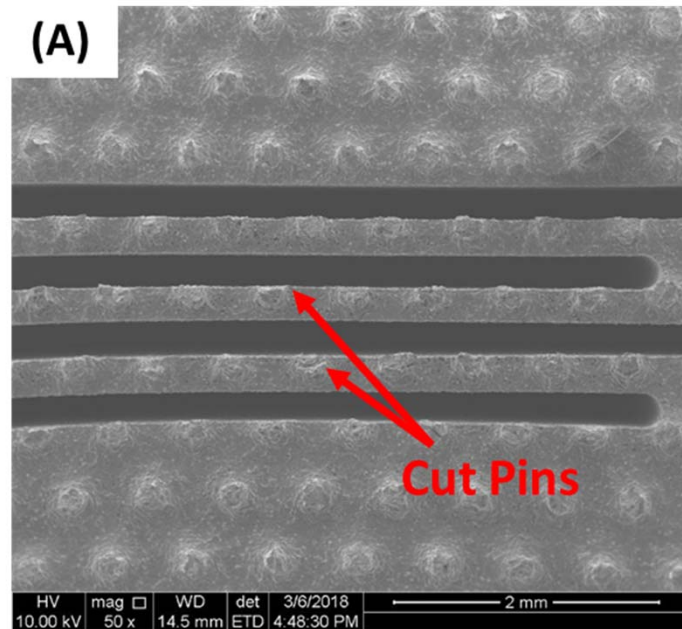
- Al-oxide in poorly bonded region
- Limited ductility in failure

Failure Related to TLP



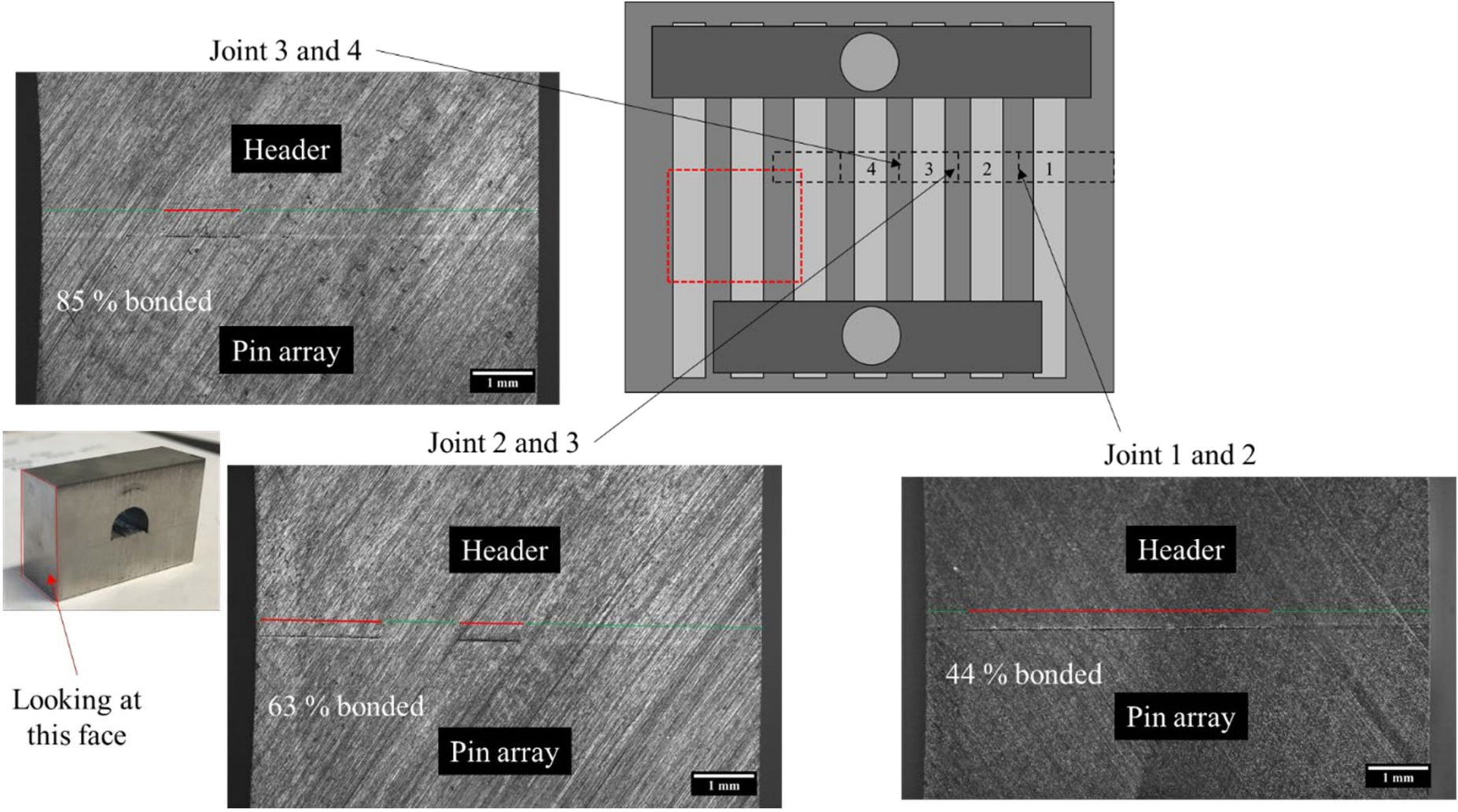
- Slow/uneven diffusion of Phosphorous could yield an incomplete bond
- Bond could re-liquefy during braze or heat treatment
 - Slippage
 - Voids
 - O₂ ingress easier
- **ACTION:** Faster diffusing MPD or solid diffusion bond

Failure Related to Design



- Inlet/outlet slit region sensitive to manufacturing defects
- Pin array ideal for HT and ΔP , but not robust.

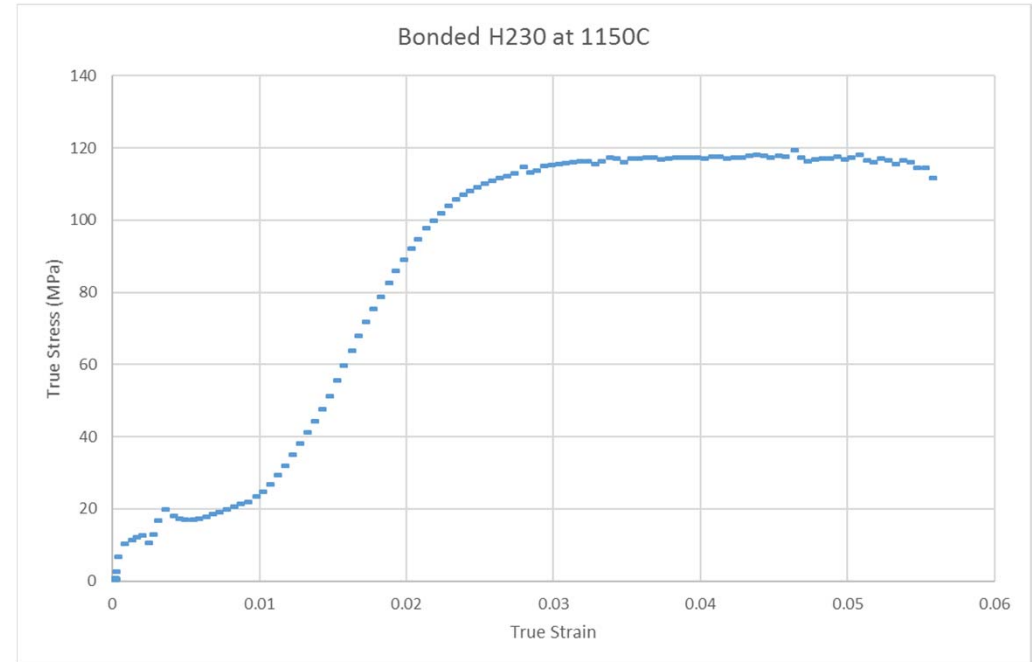
Failure Related to Braze



Failure Mode Mitigation

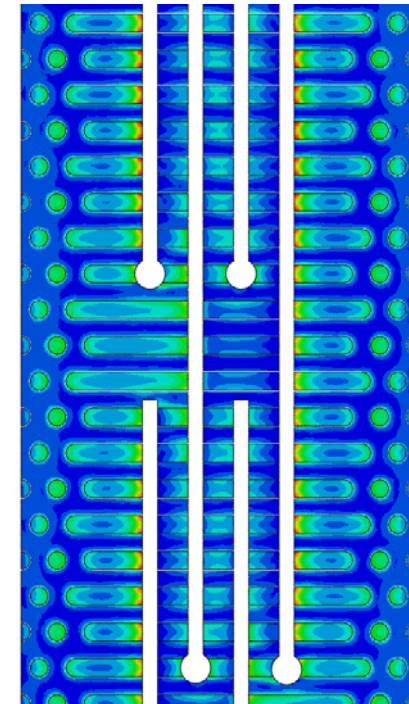
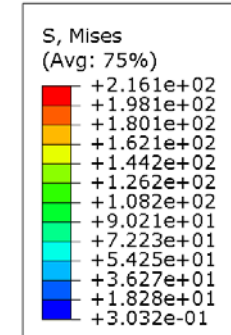
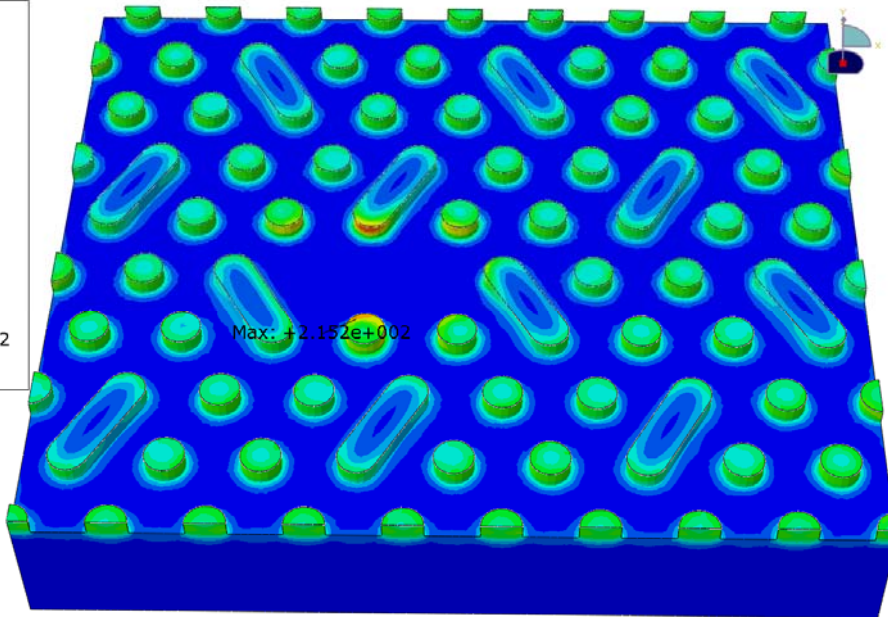
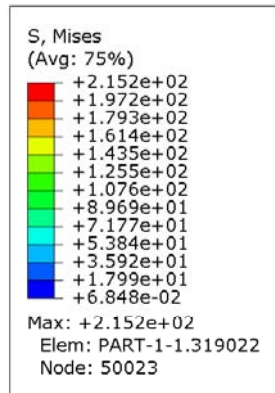
Failure Mode Identifier	Description
A	Liquification w/o bonding pressure (unbonded and poorly bonded pins)
B	Aluminum oxide formation
C	Voids
D	Cut pins due to wire EDM
E	Carbon contamination due to wire EDM
F	Insufficient safety factor for “missing” pins
G	Insufficient bonding pressure in slit region

Diffusion Bonding



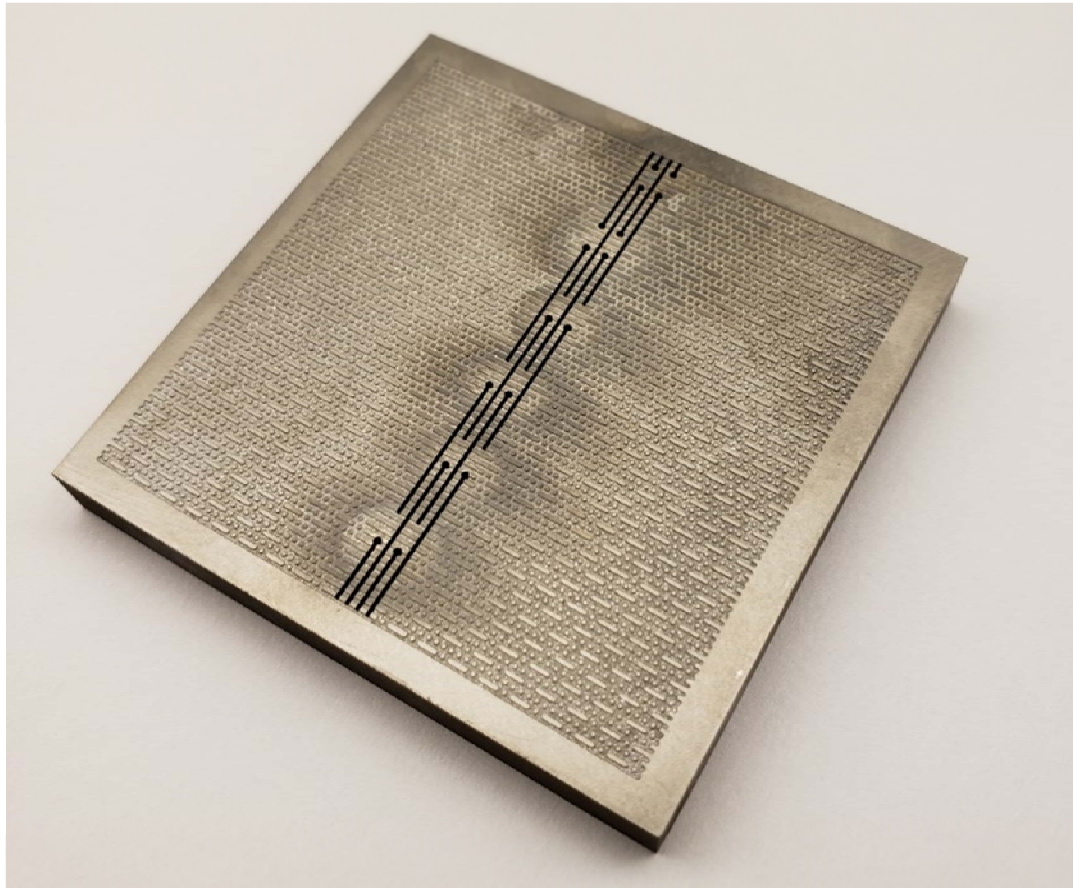
- Concerns with Boron as MPD for TLP due to fast diffusion
- Move to solid diffusion bonding with and w/o nickel interlayer
- Solid joint at 1150 °C
- Good joint yield/ductility at 720 °C

Design Modifications

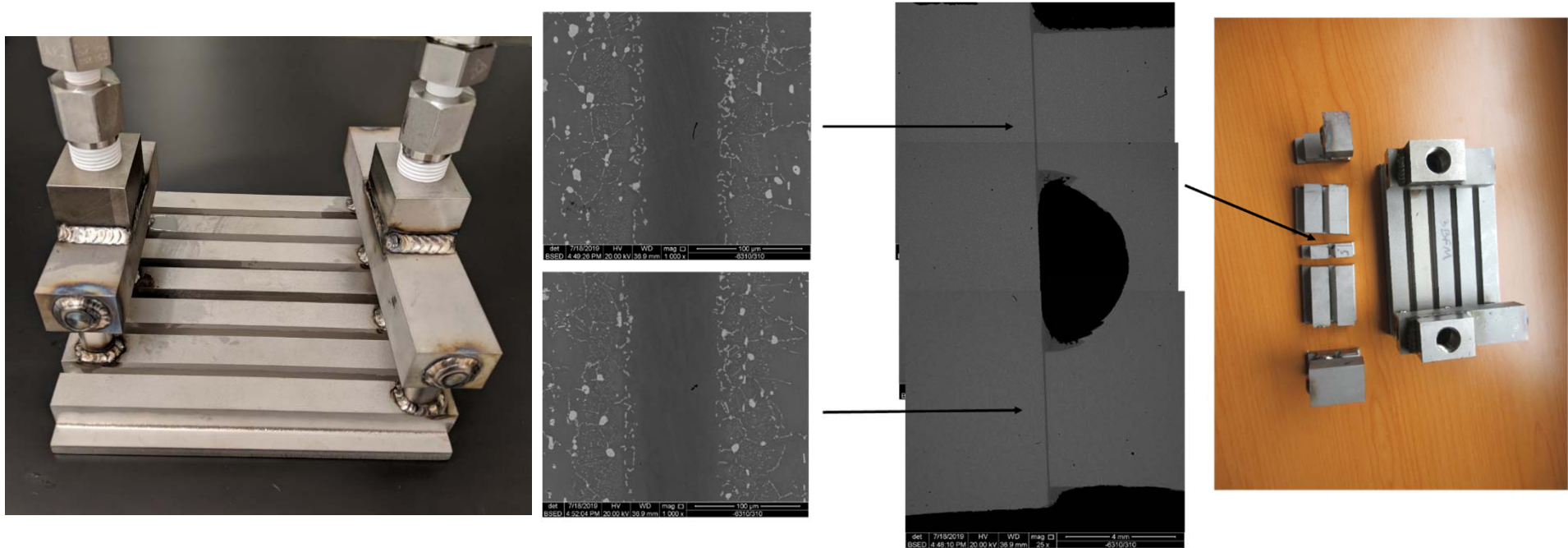


- Pin and bar more robust
- Inlet/outlet slit bonding area increased
- Qualification testing ongoing

Design Modifications



Revised Brazing Methods



- Added heat treatment (stress relief) steps
- Increased braze thickness
- Improved surface prep
- Pass proof test >83 MPa at RT
- Good joint quality

Looking Forward

- Pathway to megawatt scale demonstrated
- Modular concept advantageous
 - Tailored receiver design
 - Manufacturability
- Physical test article designed and fabricated
- On-sun testing at UC-Davis in Q4 2019



Conclusions

- High temperature/pressure sCO₂ heat exchanger development is challenging and expensive
- Solar thermal application even more extreme than other devices
- Printed circuit type HX with challenges related to
 - Joining
 - Design
- Lessons
 - Lab scale bonding may not scale to component level (uneven ramp rates, non-uniform diffusion etc.)
 - Manufacturing, thermal hydraulic and mechanical must be concurrently considered in design
 - Brazing high nickel alloys is non-trivial
- I am happy to share more detailed technical information with interested parties

Acknowledgments

- R. Malhotra (Rutgers)
- S. Apte (Oregon State)
- V. Narayanan (UC-Davis)
- E. Rasouli (UC-Davis)
- Matt Carl (NETL)



SOLAR ENERGY
TECHNOLOGIES OFFICE
U.S. Department Of Energy

Questions?

Brian.Fronk@oregonstate.edu

